



# CY62256

## 32Kx8 Static RAM

### Features

- 4.5V–5.5V Operation
- Low active power (70 ns, LL version)  
— 275 mW (max.)
- Low standby power (70 ns, LL version)  
— 28  $\mu$ W (max.)
- 55, 70 ns access time
- Easy memory expansion with CE and OE features
- TTL-compatible inputs and outputs
- Automatic power-down when deselected
- CMOS for optimum speed/power

### Functional Description

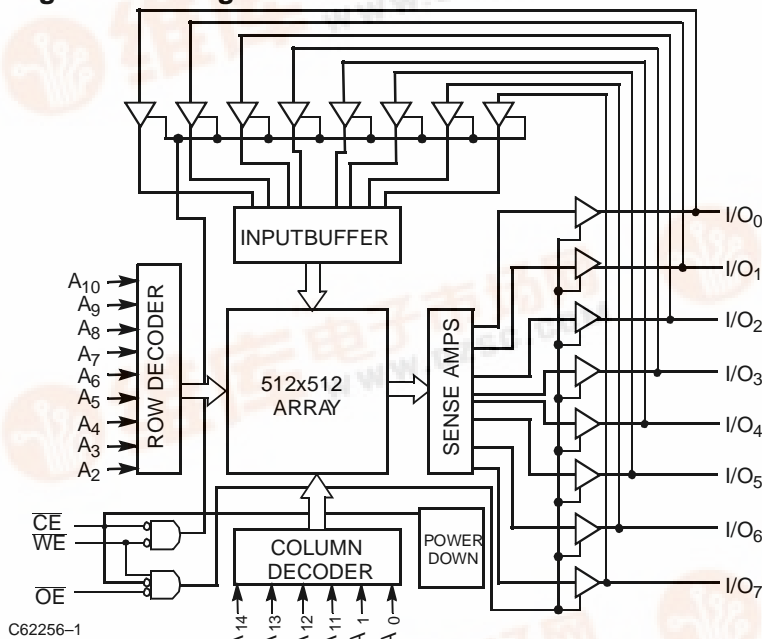
The CY62256 is a high-performance CMOS static RAM organized as 32,768 words by 8 bits. Easy memory expansion is provided by an active LOW chip enable ( $\overline{CE}$ ) and active LOW

output enable ( $\overline{OE}$ ) and three-state drivers. This device has an automatic power-down feature, reducing the power consumption by 99.9% when deselected. The CY62256 is in the standard 450-mil-wide (300-mil body width) SOIC, TSOP, and 600-mil PDIP packages.

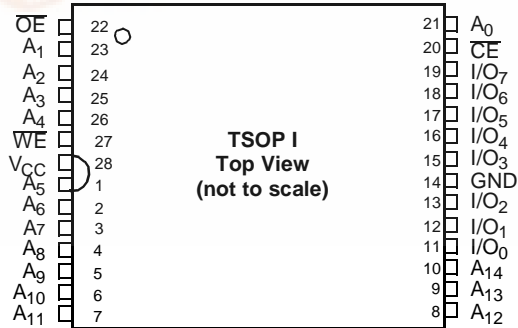
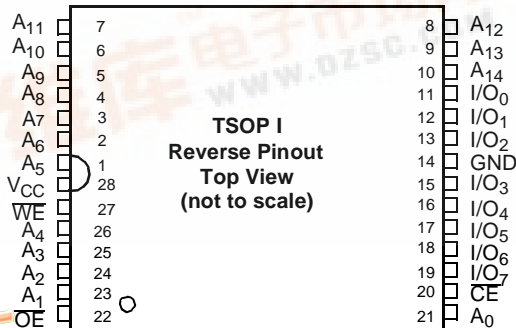
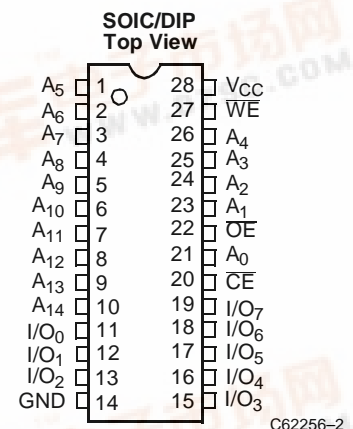
An active LOW write enable signal ( $\overline{WE}$ ) controls the writing/reading operation of the memory. When  $\overline{CE}$  and  $\overline{WE}$  inputs are both LOW, data on the eight data input/output pins ( $I/O_0$  through  $I/O_7$ ) is written into the memory location addressed by the address present on the address pins ( $A_0$  through  $A_{14}$ ). Reading the device is accomplished by selecting the device and enabling the outputs,  $\overline{CE}$  and  $\overline{OE}$  active LOW, while  $\overline{WE}$  remains inactive or HIGH. Under these conditions, the contents of the location addressed by the information on address pins are present on the eight data input/output pins.

The input/output pins remain in a high-impedance state unless the chip is selected, outputs are enabled, and write enable ( $\overline{WE}$ ) is HIGH.

### Logic Block Diagram



### Pin Configurations





## Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature ..... -65°C to +150°C

Ambient Temperature with  
Power Applied ..... 0°C to +70°C

Supply Voltage to Ground Potential  
(Pin 28 to Pin 14) ..... -0.5V to +7.0V

DC Voltage Applied to Outputs  
in High Z State<sup>[1]</sup> ..... -0.5V to  $V_{CC} + 0.5V$

DC Input Voltage<sup>[1]</sup> ..... -0.5V to  $V_{CC} + 0.5V$

Output Current into Outputs (LOW) ..... 20 mA

Static Discharge Voltage ..... >2001V  
(per MIL-STD-883, Method 3015)

Latch-Up Current ..... >200 mA

## Operating Range

Range	Ambient Temperature	$V_{CC}$
Commercial	0°C to +70°C	5V ± 10%
Industrial	-40°C to +85°C	5V ± 10%

## Electrical Characteristics Over the Operating Range

Parameter	Description	Test Conditions	CY62256-55			CY62256-70			Unit
			Min.	Typ <sup>[2]</sup>	Max.	Min.	Typ <sup>[2]</sup>	Max.	
$V_{OH}$	Output HIGH Voltage	$V_{CC} = \text{Min.}, I_{OH} = -1.0 \text{ mA}$	2.4			2.4			V
$V_{OL}$	Output LOW Voltage	$V_{CC} = \text{Min.}, I_{OL} = 2.1 \text{ mA}$			0.4			0.4	V
$V_{IH}$	Input HIGH Voltage		2.2		$V_{CC} + 0.5V$	2.2		$V_{CC} + 0.5V$	V
$V_{IL}$	Input LOW Voltage		-0.5		0.8	-0.5		0.8	V
$I_{IX}$	Input Load Current	$GND \leq V_I \leq V_{CC}$	-0.5		+0.5	-0.5		+0.5	μA
$I_{OZ}$	Output Leakage Current	$GND \leq V_O \leq V_{CC}$ , Output Disabled	-0.5		+0.5	-0.5		+0.5	μA
$I_{CC}$	$V_{CC}$ Operating Supply Current	$V_{CC} = \text{Max.}, I_{OUT} = 0 \text{ mA}, f = f_{MAX} = 1/t_{RC}$		28	55		28	55	mA
			L	25	50		25	50	mA
			LL	25	50		25	50	mA
$I_{SB1}$	Automatic CE Power-Down Current—TTL Inputs	Max. $V_{CC}$ , $\overline{CE} \geq V_{IH}$ , $V_{IN} \geq V_{IH}$ or $V_{IN} \leq V_{IL}$ , $f = f_{MAX}$		0.5	2		0.5	2	mA
			L	0.4	0.6		0.4	0.6	mA
			LL	0.3	0.5		0.3	0.5	mA
$I_{SB2}$	Automatic CE Power-Down Current—CMOS Inputs	Max. $V_{CC}$ , $\overline{CE} \geq V_{CC} - 0.3V$ , $V_{IN} \geq V_{CC} - 0.3V$ or $V_{IN} \leq 0.3V$ , $f = 0$		1	5		1	5	mA
			L	2	50		2	50	μA
			LL	0.1	5		0.1	5	μA
		Indust'l Temp Range	LL	0.1	10		0.1	10	μA

Shaded area contains preliminary information.

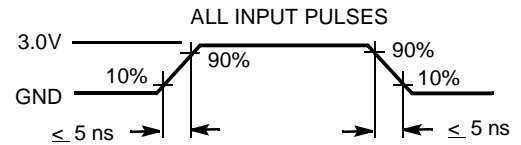
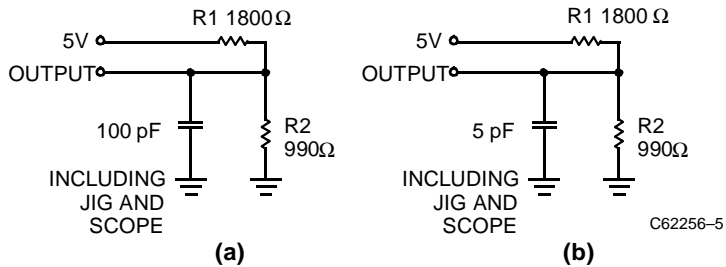
## Capacitance<sup>[3]</sup>

Parameter	Description	Test Conditions	Max.	Unit
$C_{IN}$	Input Capacitance	$T_A = 25^\circ\text{C}, f = 1 \text{ MHz}, V_{CC} = 5.0V$	6	pF
$C_{OUT}$	Output Capacitance		8	pF

### Note:

- $V_{IL}(\text{min.}) = -2.0V$  for pulse durations of less than 20 ns.
- Typical specifications are the mean values measured over a large sample size across normal production process variations and are taken at nominal conditions ( $T_A = 25^\circ\text{C}, V_{CC}$ ). Parameters are guaranteed by design and characterization, and not 100% tested.
- Tested initially and after any design or process changes that may affect these parameters.

## AC Test Loads and Waveforms

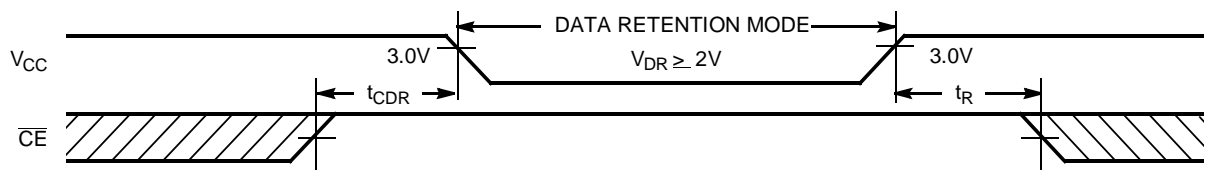


Equivalent to: THÉVENIN EQUIVALENT  
 639Ω  
 OUTPUT ——— 1.77V

## Data Retention Characteristics

Parameter	Description		Conditions <sup>[4]</sup>	Min.	Typ. <sup>[2]</sup>	Max.	Unit
V <sub>DR</sub>	V <sub>CC</sub> for Data Retention		V <sub>CC</sub> = 3.0V, CE ≥ V <sub>CC</sub> − 0.3V, V <sub>IN</sub> ≥ V <sub>CC</sub> − 0.3V or V <sub>IN</sub> ≤ 0.3V	2.0			V
I <sub>CCDR</sub>	Data Retention Current	L			2	50	μA
		LL			0.1	5	μA
		LL Indust'l			0.1	10	μA
t <sub>CDR</sub> <sup>[3]</sup>	Chip Deselect to Data Retention Time			0			ns
t <sub>R</sub> <sup>[3]</sup>	Operation Recovery Time		t <sub>RC</sub>			ns	

## Data Retention Waveform



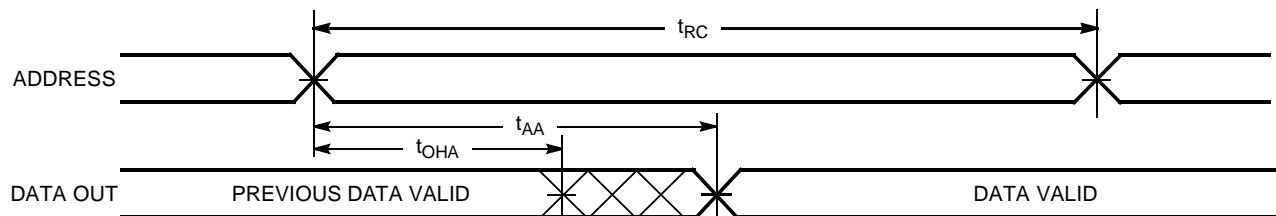
### Note:

- No input may exceed V<sub>CC</sub>+0.5V.

**Switching Characteristics** Over the Operating Range<sup>[5]</sup>

Parameter	Description	CY62256–55		CY62256–70		Unit
		Min.	Max.	Min.	Max.	
READ CYCLE						
t <sub>RC</sub>	Read Cycle Time	55		70		ns
t <sub>AA</sub>	Address to Data Valid		55		70	ns
t <sub>OHA</sub>	Data Hold from Address Change	5		5		ns
t <sub>ACE</sub>	$\overline{CE}$ LOW to Data Valid		55		70	ns
t <sub>DOE</sub>	$\overline{OE}$ LOW to Data Valid		25		35	ns
t <sub>LZOE</sub>	$\overline{OE}$ LOW to Low Z <sup>[6]</sup>	5		5		ns
t <sub>HZOE</sub>	$\overline{OE}$ HIGH to High Z <sup>[6, 7]</sup>		20		25	ns
t <sub>LZCE</sub>	$\overline{CE}$ LOW to Low Z <sup>[6]</sup>	5		5		ns
t <sub>HZCE</sub>	$\overline{CE}$ HIGH to High Z <sup>[6, 7]</sup>		20		25	ns
t <sub>PU</sub>	$\overline{CE}$ LOW to Power-Up	0		0		ns
t <sub>PD</sub>	$\overline{CE}$ HIGH to Power-Down		55		70	ns
WRITE CYCLE <sup>[8, 9]</sup>						
t <sub>WC</sub>	Write Cycle Time	55		70		ns
t <sub>SCE</sub>	$\overline{CE}$ LOW to Write End	45		60		ns
t <sub>AW</sub>	Address Set-Up to Write End	45		60		ns
t <sub>HA</sub>	Address Hold from Write End	0		0		ns
t <sub>SA</sub>	Address Set-Up to Write Start	0		0		ns
t <sub>PWE</sub>	$\overline{WE}$ Pulse Width	40		50		ns
t <sub>SD</sub>	Data Set-Up to Write End	25		30		ns
t <sub>HD</sub>	Data Hold from Write End	0		0		ns
t <sub>HZWE</sub>	$\overline{WE}$ LOW to High Z <sup>[6, 7]</sup>		20		25	ns
t <sub>LZWE</sub>	$\overline{WE}$ HIGH to Low Z <sup>[6]</sup>	5		5		ns

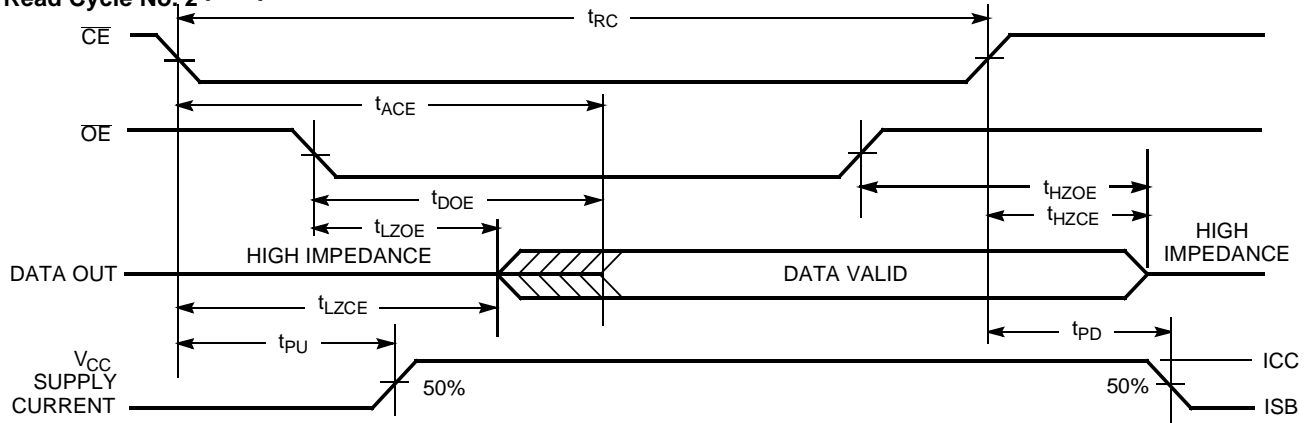
Shaded area contains preliminary information.

**Switching Waveforms**
**Read Cycle No. 1<sup>[10,11]</sup>**


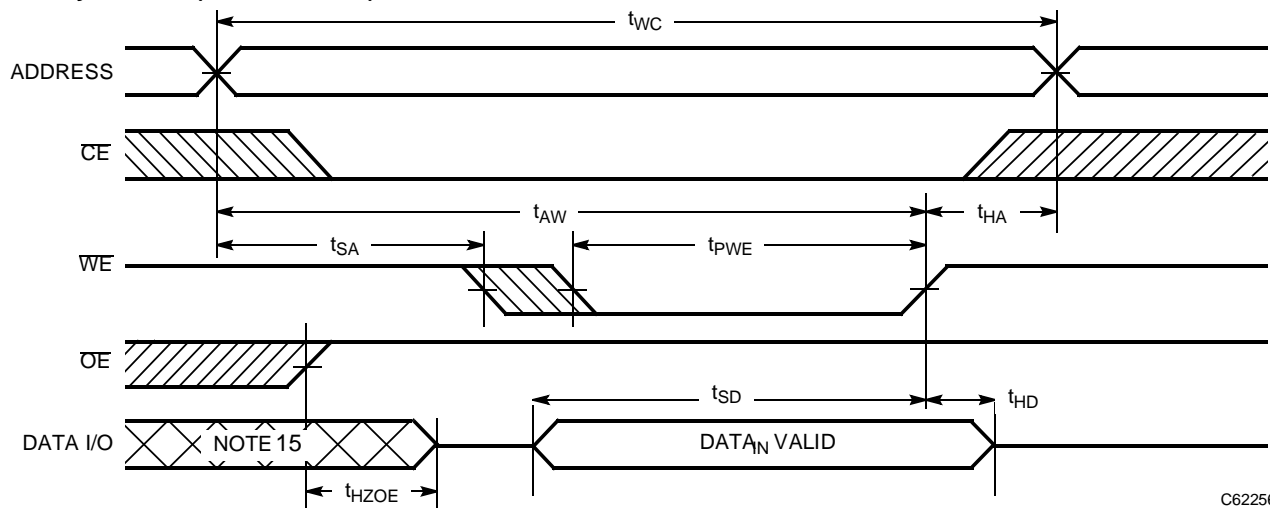
C62256–8

**Notes:**

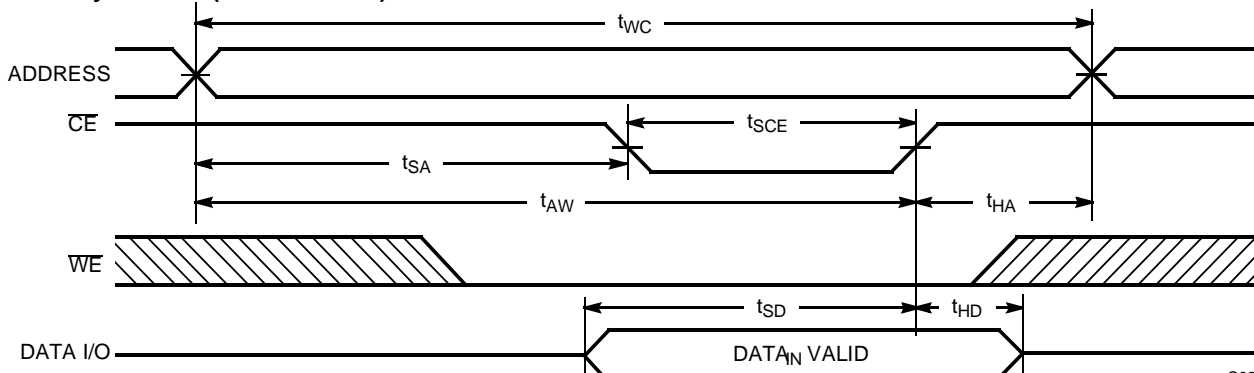
- Test conditions assume signal transition time of 5 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified  $I_{OL}/I_{OH}$  and 100-pF load capacitance.
- At any given temperature and voltage condition,  $t_{HZCE}$  is less than  $t_{LZCE}$ ,  $t_{HZOE}$  is less than  $t_{LZOE}$ , and  $t_{HZWE}$  is less than  $t_{LZWE}$  for any given device.
- $t_{HZOE}$ ,  $t_{HZCE}$ , and  $t_{HZWE}$  are specified with  $C_L = 5$  pF as in part (b) of AC Test Loads. Transition is measured  $\pm 500$  mV from steady-state voltage.
- The internal write time of the memory is defined by the overlap of  $\overline{CE}$  LOW and  $\overline{WE}$  LOW. Both signals must be LOW to initiate a write and either signal can terminate a write by going HIGH. The data input set-up and hold timing should be referenced to the rising edge of the signal that terminates the write.
- The minimum write cycle time for write cycle #3 ( $\overline{WE}$  controlled,  $\overline{OE}$  LOW) is the sum of  $t_{HZWE}$  and  $t_{SD}$ .
- Device is continuously selected.  $\overline{OE}$ ,  $\overline{CE} = V_{IL}$ .
- $\overline{WE}$  is HIGH for read cycle.

**Switching Waveforms (continued)**
**Read Cycle No. 2** [11,12]


C62256-9

**Write Cycle No. 1 (WE Controlled)** [8,13,14]


C62256-10

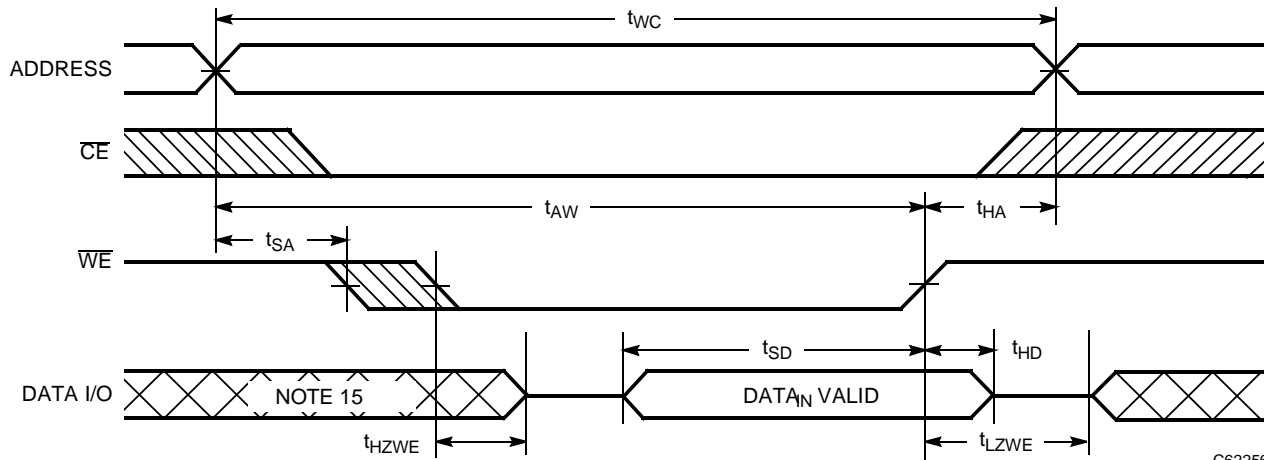
**Write Cycle No. 2 (CE Controlled)** [8,13,14]


C62256-11

**Notes:**

12. Address valid prior to or coincident with  $\overline{CE}$  transition LOW.
13. Data I/O is high impedance if  $\overline{OE} = V_{IH}$ .
14. If  $\overline{CE}$  goes HIGH simultaneously with  $\overline{WE}$  HIGH, the output remains in a high-impedance state.

**Switching Waveforms** (continued)

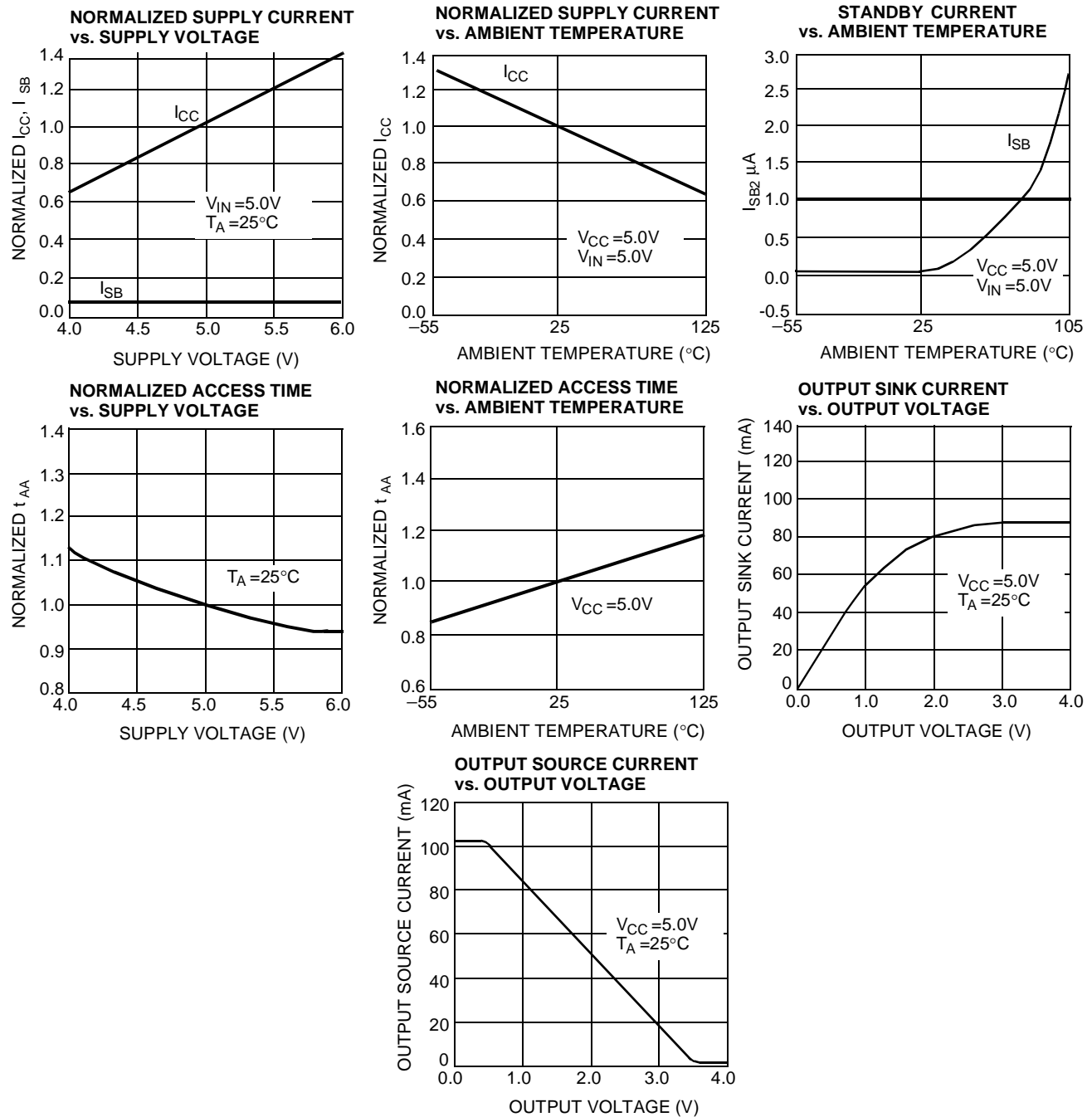
**Write Cycle No. 3 (WE Controlled, OE LOW)** <sup>[9,14]</sup>


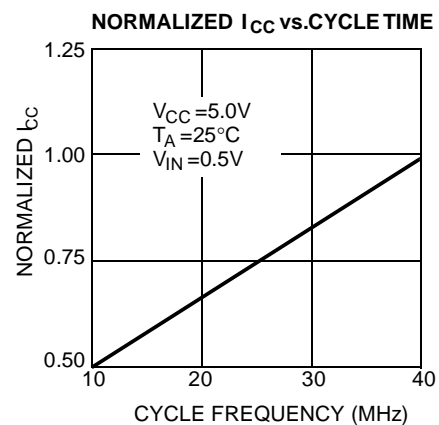
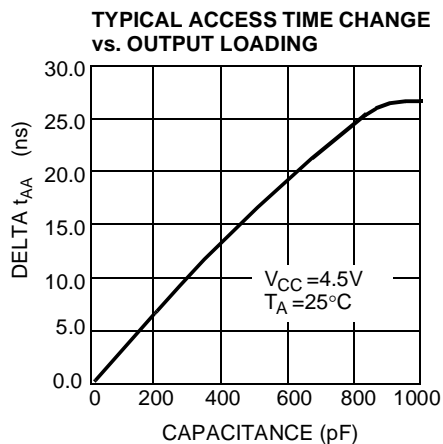
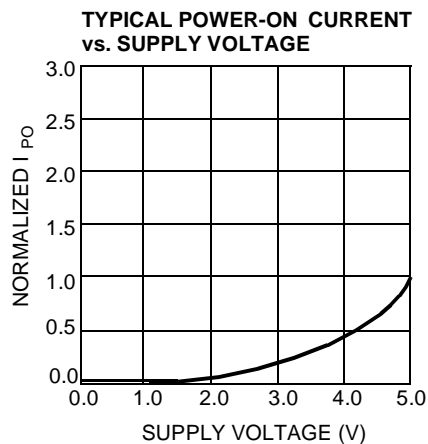
C62256-12

**Note:**

15. During this period, the I/Os are in output state and input signals should not be applied.

## Typical DC and AC Characteristics



**Typical DC and AC Characteristics** (continued)

**Truth Table**

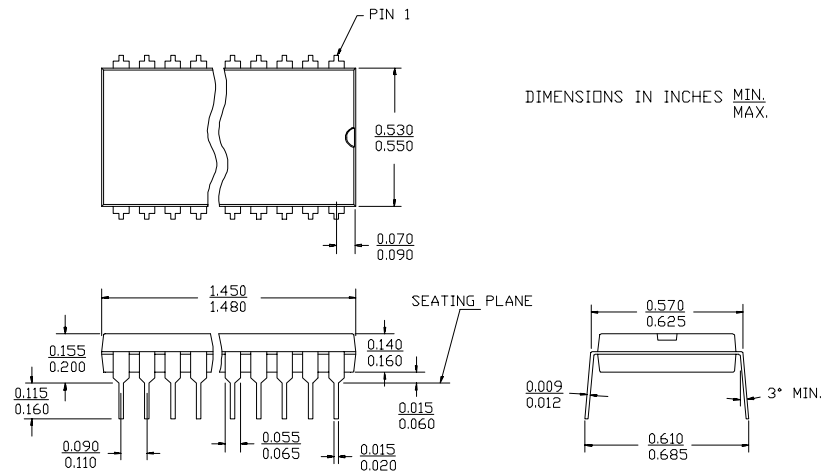
$\overline{CE}$	$\overline{WE}$	$\overline{OE}$	Inputs/Outputs	Mode	Power
H	X	X	High Z	Deselect/Power-Down	Standby ( $I_{SB}$ )
L	H	L	Data Out	Read	Active ( $I_{CC}$ )
L	L	X	Data In	Write	Active ( $I_{CC}$ )
L	H	H	High Z	Deselect, Output Disabled	Active ( $I_{CC}$ )



## Ordering Information

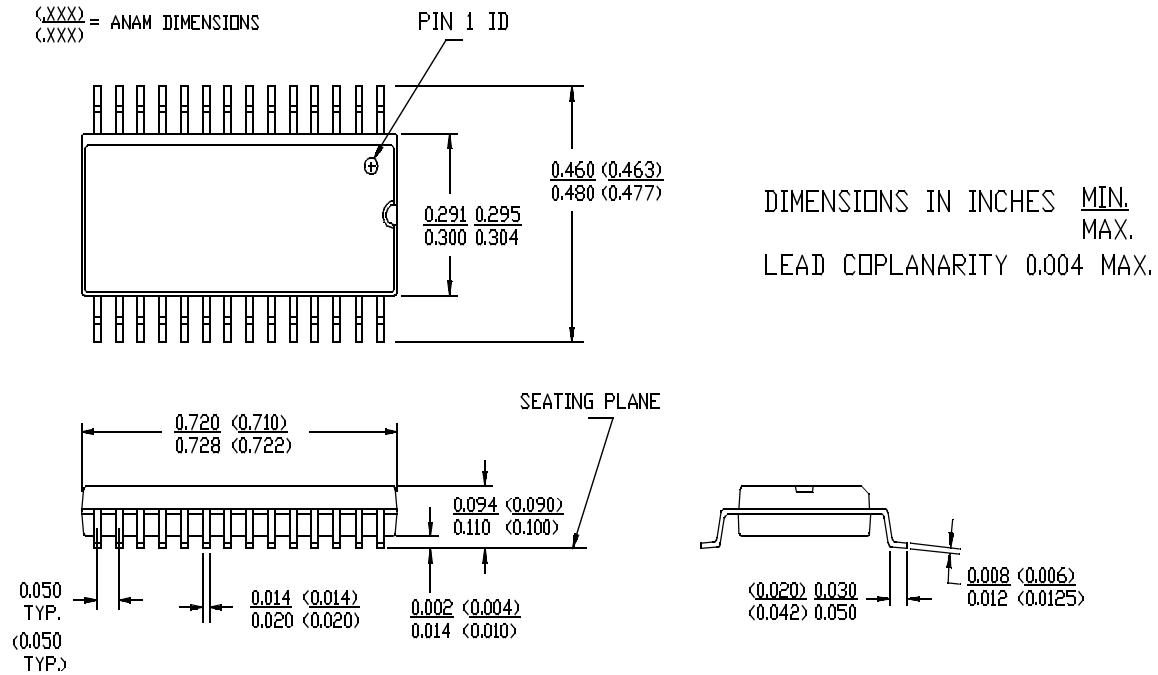
Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
55	CY62256-55SNC	S22	28-Lead 450-Mil (300-Mil Body Width) SOIC	Commercial
	CY62256L-55SNC	S22	28-Lead 450-Mil (300-Mil Body Width) SOIC	
	CY62256LL-55SNC	S22	28-Lead 450-Mil (300-Mil Body Width) SOIC	
	CY62256-55ZRC	ZR28	28-Lead Reverse Thin Small Outline Package	
	CY62256L-55ZRC	ZR28	28-Lead Reverse Thin Small Outline Package	
	CY62256LL-55ZRC	ZR28	28-Lead Reverse Thin Small Outline Package	
	CY62256-55ZC	Z28	28-Lead Thin Small Outline Package	
	CY62256L-55ZC	Z28	28-Lead Thin Small Outline Package	
	CY62256LL-55ZC	Z28	28-Lead Thin Small Outline Package	
	CY62256-55PC	P15	28-Lead (600-Mil) Molded DIP	
70	CY62256-70SNC	S22	28-Lead 450-Mil (300-Mil Body Width) SOIC	Commercial
	CY62256L-70SNC	S22	28-Lead 450-Mil (300-Mil Body Width) SOIC	
	CY62256LL-70SNC	S22	28-Lead 450-Mil (300-Mil Body Width) SOIC	
	CY62256-70SNI	S22	28-Lead 450-Mil (300-Mil Body Width) SOIC	Industrial
	CY62256L-70SNI	S22	28-Lead 450-Mil (300-Mil Body Width) SOIC	
	CY62256LL-70SNI	S22	28-Lead 450-Mil (300-Mil Body Width) SOIC	
	CY62256-70ZC	Z28	28-Lead Thin Small Outline Package	Commercial
	CY62256L-70ZC	Z28	28-Lead Thin Small Outline Package	
	CY62256LL-70ZC	Z28	28-Lead Thin Small Outline Package	
	CY62256-70ZI	Z28	28-Lead Thin Small Outline Package	Industrial
	CY62256L-70ZI	Z28	28-Lead Thin Small Outline Package	
	CY62256LL-70ZI	Z28	28-Lead Thin Small Outline Package	
	CY62256-70PC	P15	28-Lead (600-Mil) Molded DIP	Commercial
	CY62256L-70PC	P15	28-Lead (600-Mil) Molded DIP	
	CY62256LL-70PC	P15	28-Lead (600-Mil) Molded DIP	
	CY62256-70ZRC	ZR28	28-Lead Reverse Thin Small Outline Package	
	CY62256L-70ZRC	ZR28	28-Lead Reverse Thin Small Outline Package	
	CY62256LL-70ZRC	ZR28	28-Lead Reverse Thin Small Outline Package	

Shaded area contains preliminary information.

**Package Diagrams**
**28-Lead (600-Mil) Molded DIP P15**

**28-Lead 450-Mil (300-Mil Body Width) SOIC S22**

XXX = HYUNDAI DIMENSIONS  
.XXX

(.XXX) = ANAM DIMENSIONS  
(.XXX)

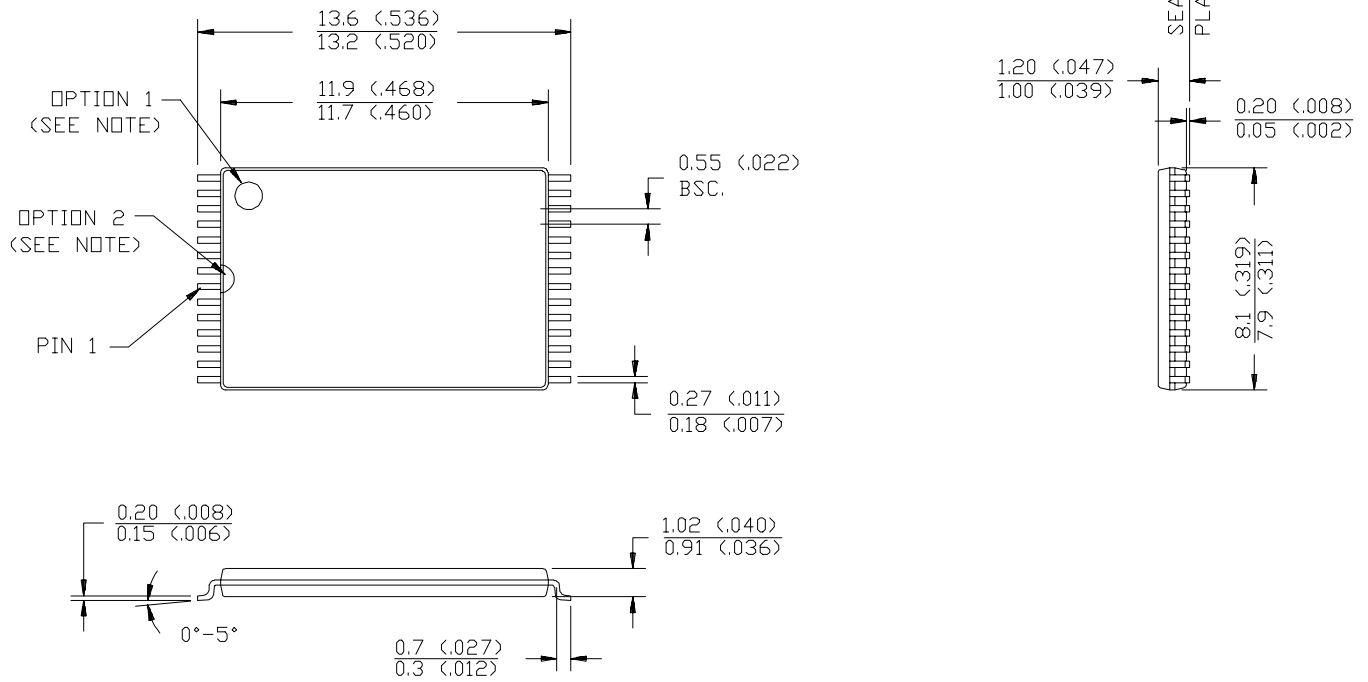


**Package Diagrams** (continued)

**28-Lead Thin Small Outline Package Z28**

NOTE: ORIENTATION I.D. MAY BE LOCATED EITHER  
AS SHOWN IN OPTION 1 OR OPTION 2

DIMENSION IN MM (INCH)  
MAX.  
MIN.



**Package Diagrams** (continued)

**28-Lead Reverse Thin Small Outline Package ZR28**

NOTE: ORIENTATION I.D MAY BE LOCATED EITHER AS SHOWN IN OPTION 1 OR OPTION 2

DIMENSION IN MM (INCH)  
MAX.  
MIN.

